	Application No.	[A
	Application No.	Applicant(s)
Notice of Allowability	09/746,228	NAKAMURA ET AL.
	Examiner	Art Unit
	Wesley D Markham	1762
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication GHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. This communication is responsive to applicant's amendment	nts of 4/16/04 and 4/21/04.	
2. 🔀 The allowed claim(s) is/are <u>14,19-22 and 26-32</u> .		
3. \boxtimes The drawings filed on <u>16 April 2004</u> are accepted by the Ex	caminer.	
 4. Acknowledgment is made of a claim for foreign priority un a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 	been received. been received in Application No	
Applicant has THREE MONTHS FROM THE "MAILING DATE" on noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a reply ENT of this application.	complying with the requirements
 A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give 	itted. Note the attached EXAMINER as reason(s) why the oath or declara	'S AMENDMENT or NOTICE OF tion is deficient.
 CORRECTED DRAWINGS (as "replacement sheets") mus (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the 	on's Patent Drawing Review (PTO- s Amendment / Comment or in the C	Office action of age in the front (not the back) of
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I 		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/OPaper No./Mail Date	6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☐ Examiner's Amendr	ie
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DETAILED ACTION / ALLOWANCE

Response to Amendment

1. Acknowledgement is made of the amendment (4/16/2004) and the supplemental amendment (4/21/2004) filed by the applicant in the instant application, which resulted in (1) the cancellation of Claims 13, 15 – 18, and 23 – 25, (2) the amendment of Claim 28, and (3) the addition and subsequent amendment of Claims 29 – 32. Claims 14, 19 – 22, and 26 – 32 are currently pending in U.S. Application Serial No. 09/746,228, and an Office Action on the merits follows.

Drawings

2. The replacement sheet of drawings (1 sheet, 3 total figures) filed by the applicant on 4/16/2004 is acknowledged and approved by the examiner.

Allowable Subject Matter

- 3. Claims 14, 19 22, and 26 32 are allowed.
- 4. The following is an examiner's statement of reasons for allowance: Independent Claims 14 (from which Claims 19 22 and 26 31 depend) and 32 are drawn to a method for producing a transparent laminate. The claimed method comprises depositing a high refractive index transparent thin film by a vacuum dry process, depositing a silver transparent conductive thin film by a vacuum dry process, repeating the aforementioned deposition steps at least three times to thereby form at least three combination thin film layers of the high refractive index thin film and the

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silver transparent conductive thin film successively laminated on a transparent substrate, and depositing another high refractive index transparent thin film on a surface of the combination thin film layers by a vacuum dry process, wherein the temperature T (K) of the transparent substrate at the time of depositing the silver transparent conductive thin films is set to be in a range of 340 to 390 K, inclusive, and a deposition rate R (nm/sec) of the silver transparent conductive thin films is set to be R = (1/40) x $(T-300) \pm 0.5$. A summary of the closest prior art of record follows. Anzaki et al. (USPN 6,316,110 B1) teaches a method for producing a transparent laminate, specifically an electromagnetic wave filter for a plasma display panel (Abstract), the method comprising the steps of preparing a transparent substrate (Col.1, lines 5 – 15, Col.3, lines 10 – 11), depositing a transparent dielectric layer having a refractive index of up to 2.8 (i.e., a "high refractive index" film) on the substrate, depositing a silver transparent conductive thin film on the dielectric layer. repeating the aforementioned steps three times to obtain three combination thin film layers on the substrate, and depositing another transparent dielectric layer (i.e., "high refractive index" film) on the combination thin film layers (Col.3, lines 1 - 25, Col.4, lines 14 – 40, Col.5, lines 1 – 9, Col.6, lines 8 – 12 and 45 – 55, and Figure 2). The layers are deposited by a "vacuum dry process" such as sputtering (Col.6, lines 13 – 29) while heating the substrate to a temperature of 300° C (i.e., 573 K) or lower during the silver film formation (Col.6, lines 20 - 23), a temperature range that encompasses the applicant's claimed temperature range. Okamura et al. (USPN 6,104,530) teaches a method of producing a transparent laminate, specifically an

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optical filter (Abstract), the method comprising the steps of preparing a transparent substrate (Abstract), depositing a high refractive index transparent film, depositing a silver transparent conductive film on the high refractive index transparent film, repeating the aforementioned deposition steps three to six times to form three to six combination thin film layers on the substrate, and depositing another high-refractive index transparent film on the surface of the combination thin film layers (Abstract, Col.4, lines 38 – 54, Col.5, lines 1 – 5, Cols.6 – 7, Col.9, lines 18 – 67, Col.27, lines 6 – 67, Col.28, lines 1 – 14, and Figure 2). The layers are deposited by a "vacuum" dry process" such as sputtering (Col.11, lines 45 – 67, and Col.12, lines 1 – 8), and Okamura et al. is silent regarding the temperature of the substrate during the sputtering process(es). However, neither Okamura et al. nor Anzaki et al., alone or in combination, teaches or reasonably suggests performing such processes of producing a transparent laminate both at the applicant's claimed substrate temperature and at the applicant's claimed temperature-dependent deposition rate. a combination of which allows the claimed method to advantageously produce a transparent laminate having a reduced wavelength dependence of visible light transmittance, exhibit a color tone of neutral gray, and satisfy the need for electromagnetic wave shielding, near IR cutting, and visible light low-reflectance, as disclosed by the applicant. Therefore, independent Claims 14 and 32 are allowed. Since Claims 19 - 22 and 26 - 31 depend from Claim 14, these claims are also allowed.

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5. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Wesley D Markham whose telephone number is (571) 272-1422. The examiner can normally be reached on Monday - Friday, 8:00 AM to 4:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Shrive Beck can be reached on (571) 272-1415. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Wesley D Markham Examiner Art Unit 1762 Application/Control Number: 09/746,228

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